





an Open Access Journal by MDPI

# Advanced Fault Detection, Diagnosis and Control in Industrial Electronics

Guest Editors:

#### Dr. Jose Luis Calvo-Rolle

Department of Industrial Engineering, University of A Coruña, 15405 Ferrol, Spain

## Dr. Francisco Zayas-Gato

CTC, Department of Industrial Engineering, CITIC, University of A Coruña, EPEF, Calle Mendizábal, s/n, Campus de Esteiro, Ferrol, 15403 A Coruña, Spain

Deadline for manuscript submissions:

closed (15 March 2024)

# **Message from the Guest Editors**

This Special Issue provides an exciting forum for discussion of the most recent developments and practical uses of Advanced Fault Detection, Diagnosis, and Control in Industrial Electronics

The following areas are among those that this Special Issue hopes to advance:

- diagnosis and fault identification;
- updating conventional systems;
- the development of novel intelligent control topologies and methodologies;
- modeling complex systems;
- process and method improvement;
- applications of intelligent systems to industrial operations;
- optimization of and increase in system performance;
- uses of intelligent systems;
- applications for intelligent controls;
- applications for smart grids and micro-grids;
- applications for electro-mobility and mobility;
- applied power electronics;
- Internet of Things.

https://www.mdpi.com/journal/electronics/special\_issues/9S04XNS27F



Specialsue







an Open Access Journal by MDPI

## **Editor-in-Chief**

#### Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

# **Message from the Editor-in-Chief**

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

## **Author Benefits**

**Open Access:** free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science),

CAPlus / SciFinder, Inspec, and other databases.

Journal Rank: JCR - Q2(Electrical and Electronic Engineering) CiteScore - Q2 (Electrical

and Electronic Engineering

#### **Contact Us**